

Search Notes

Application/Control No.

10/053,229

Examiner

Annan Q. Shang

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
725	95,120,13 3,141,153	2/1/2006	A.S
375	240.26	2/1/2006	A.S

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR